

Fig. 1

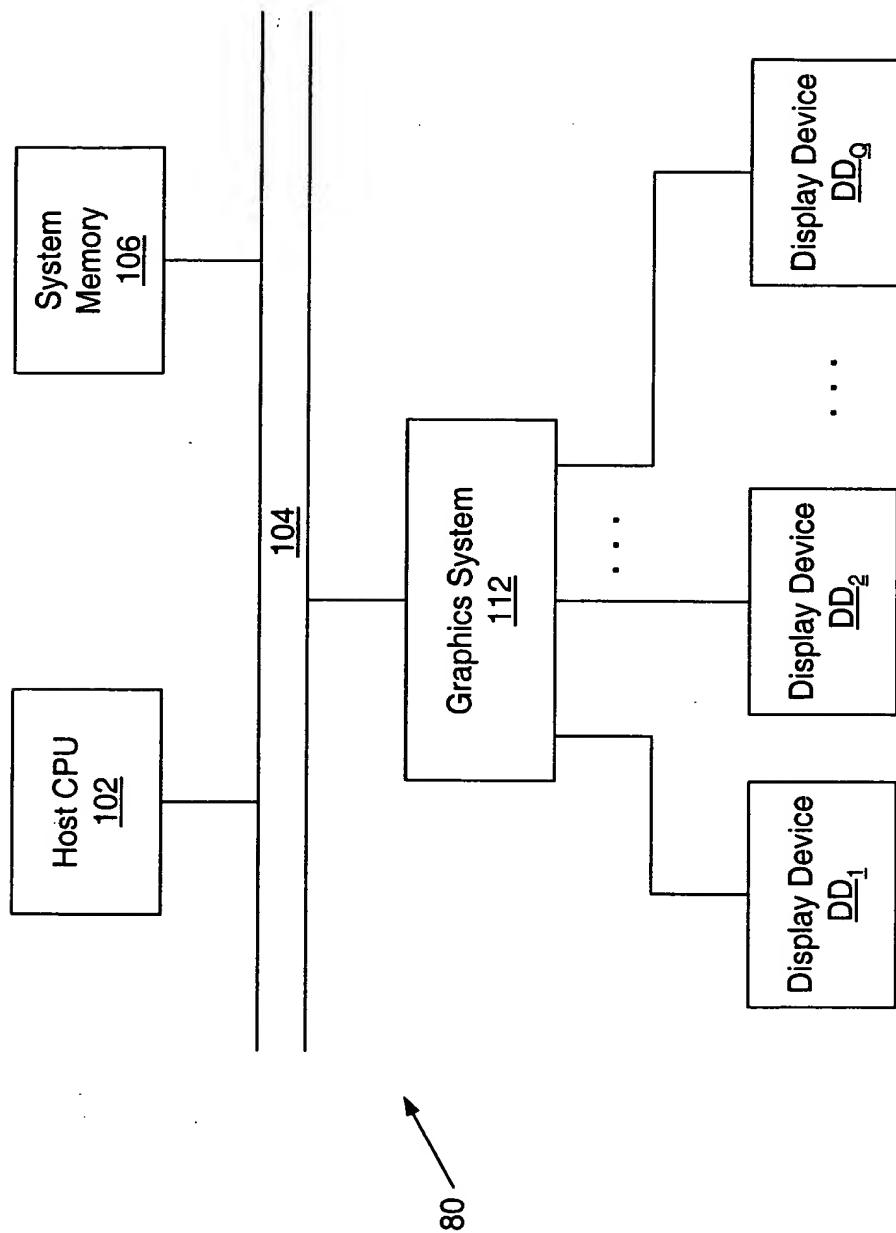


FIG. 2

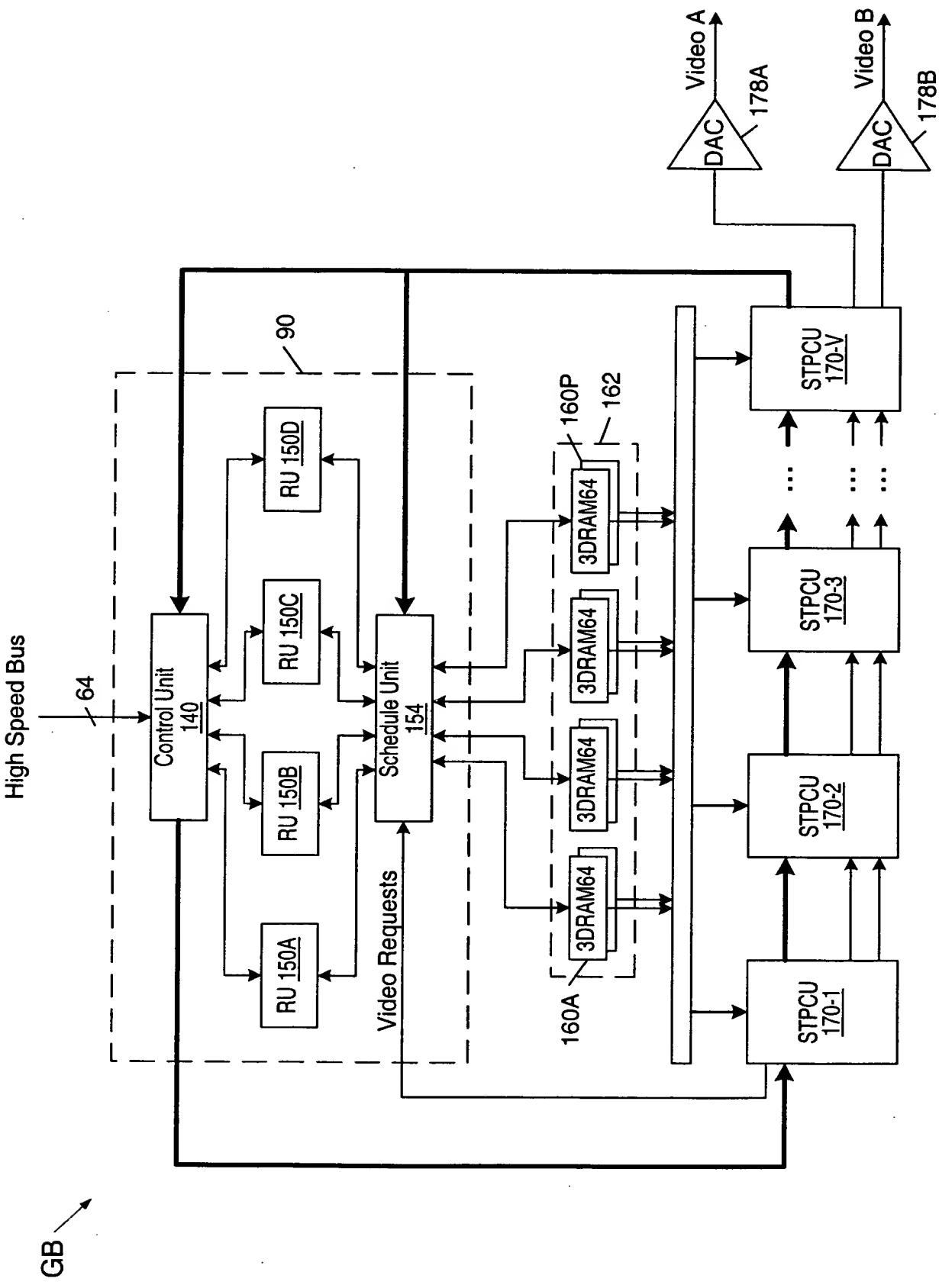
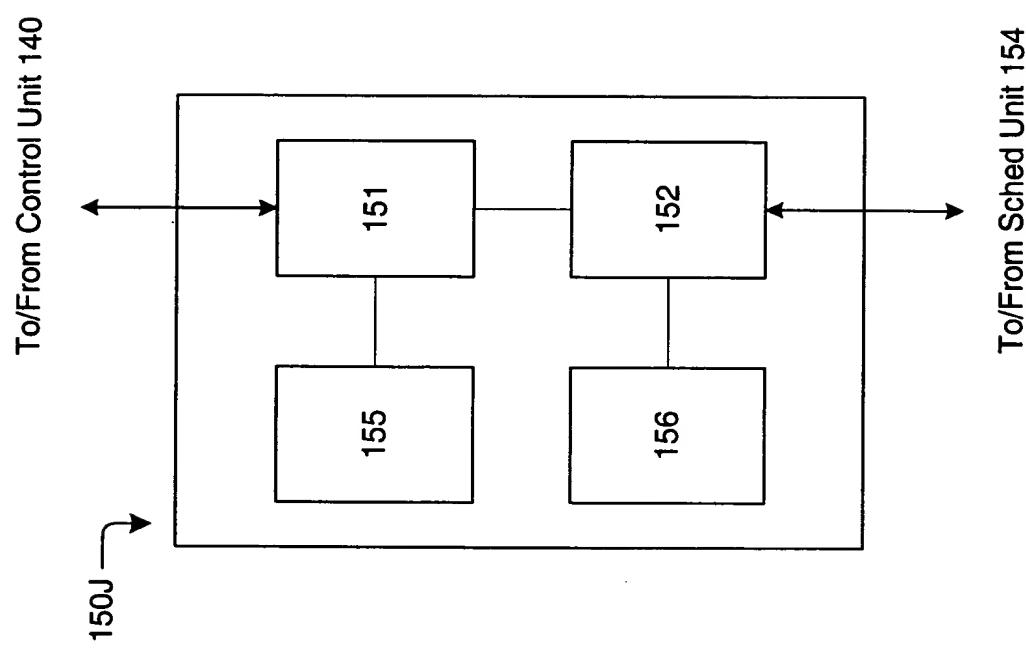
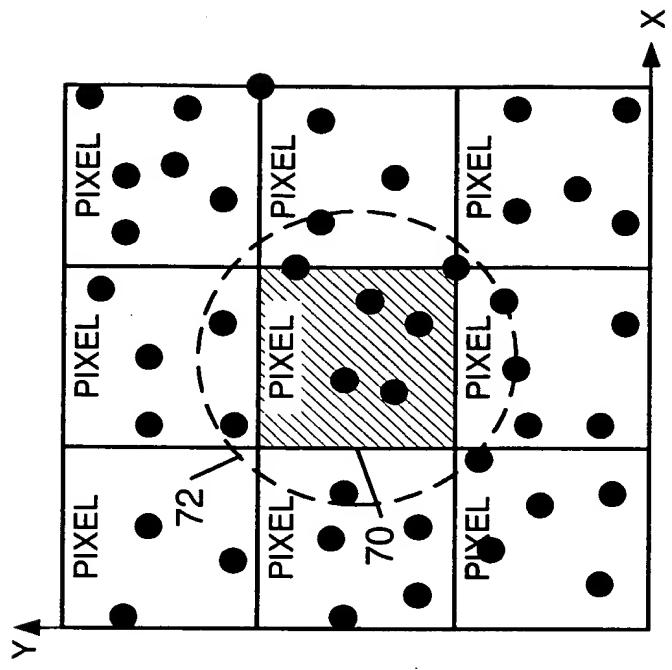
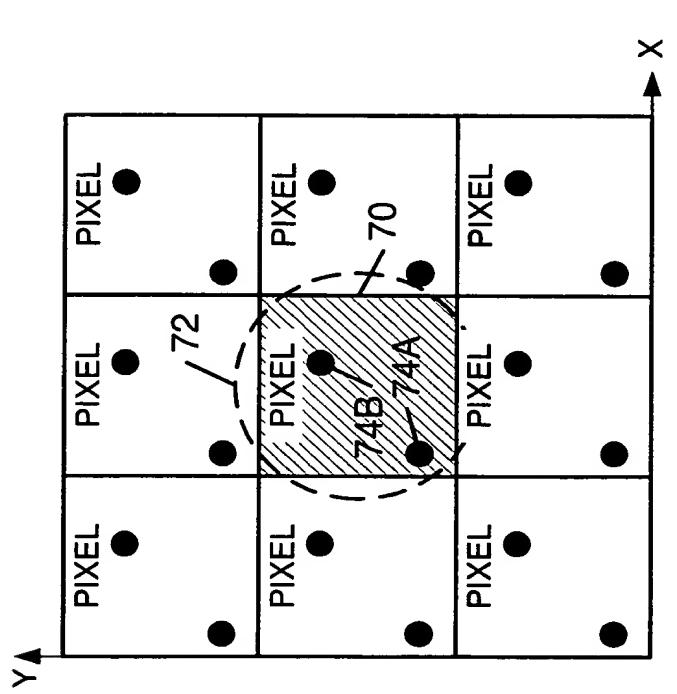
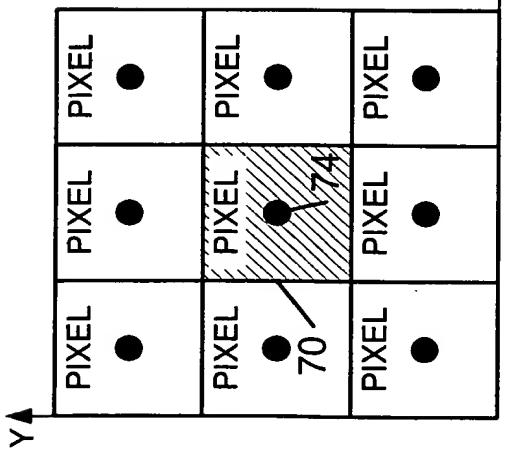


FIG. 3A

FIG. 3B





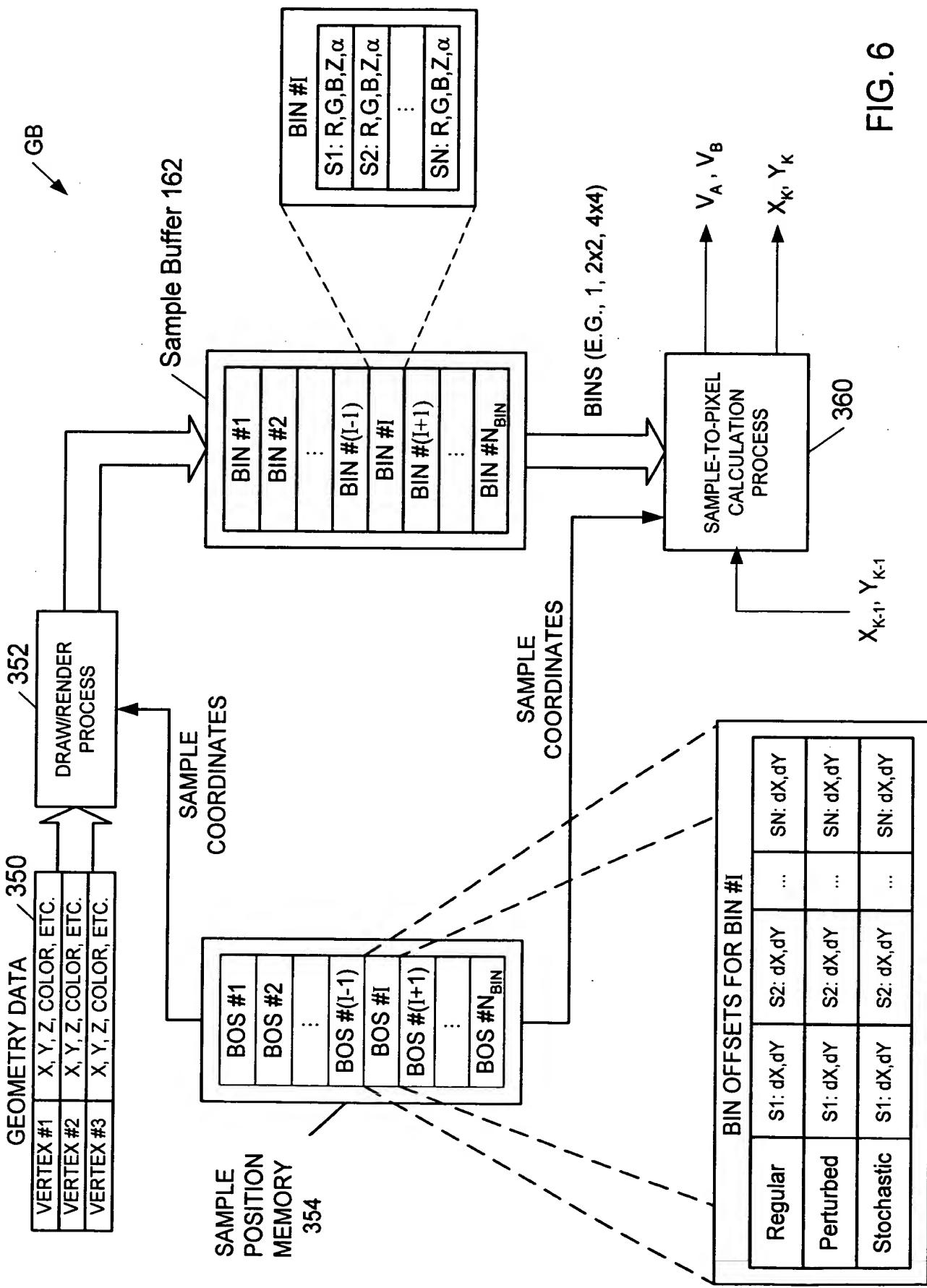


FIG. 6

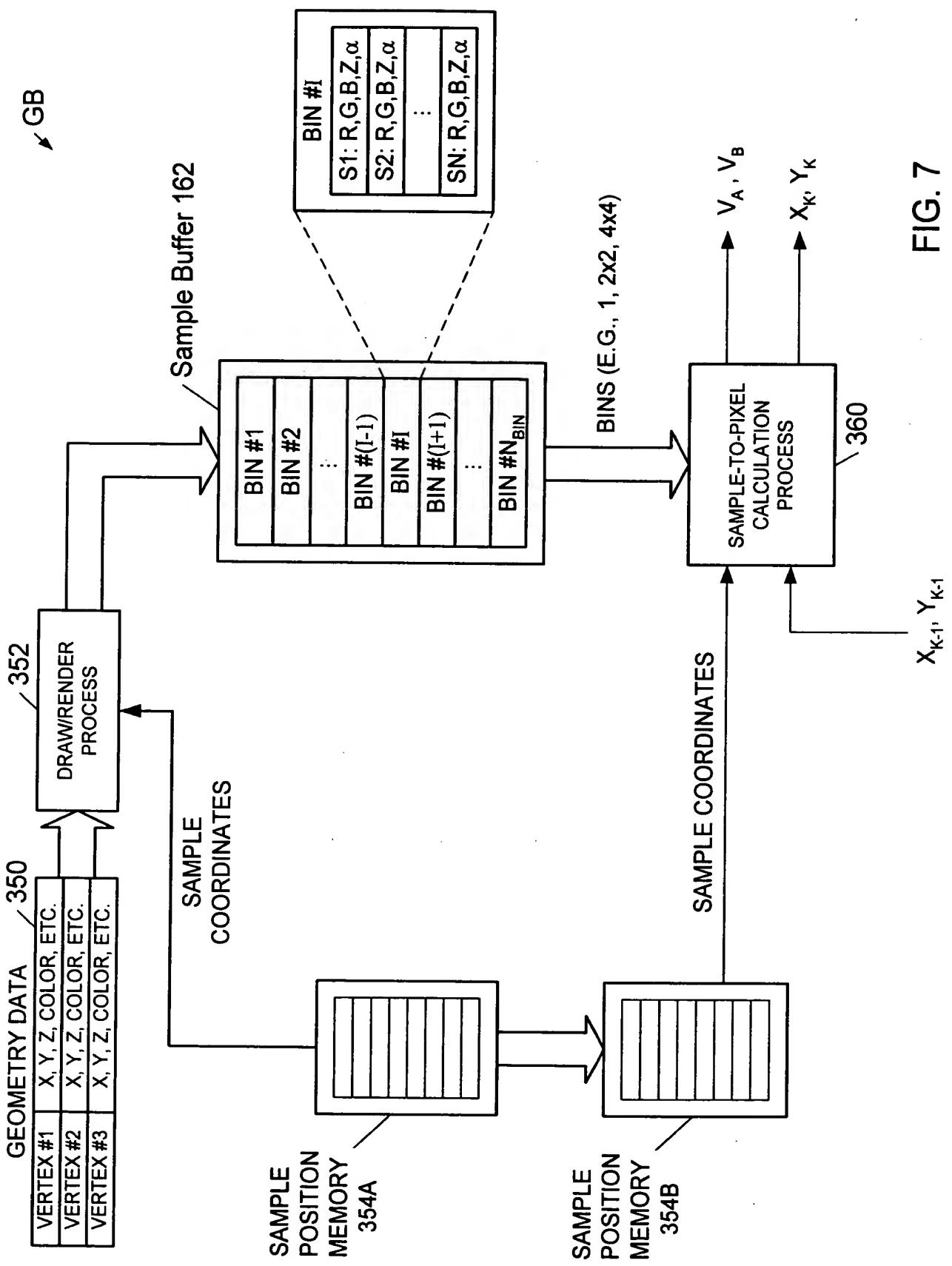
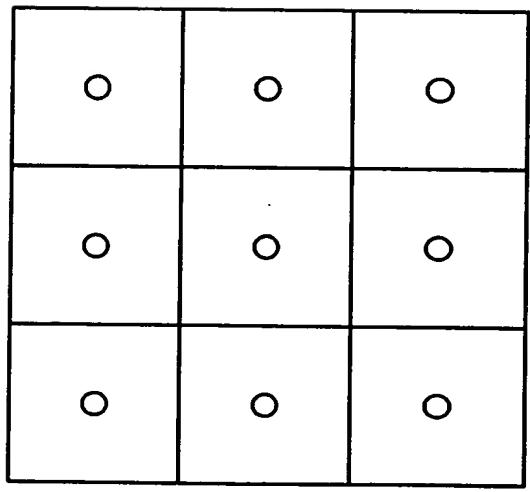
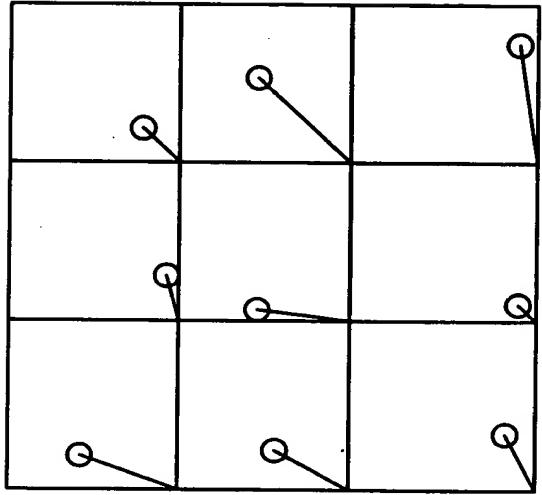


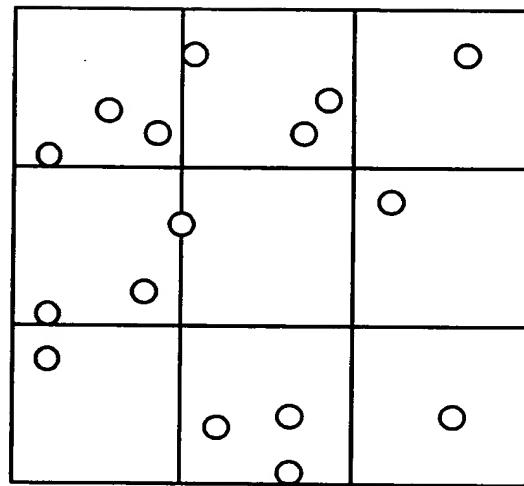
FIG. 7



Regular Sample
Positioning



Perturbed Regular
Sample Positioning



Stochastic Sample
Positioning

192

194

FIG. 8

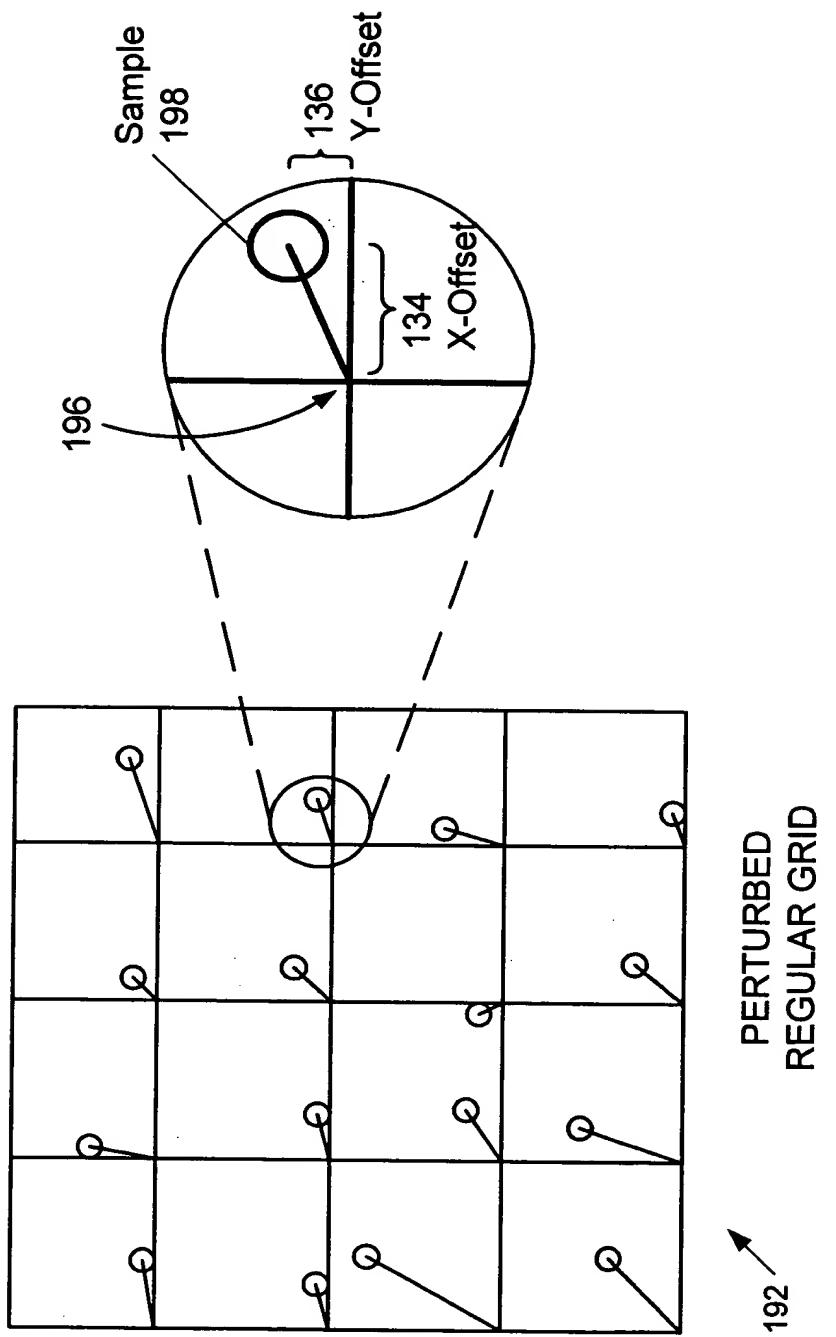


FIG. 9

PERTURBED
REGULAR GRID
192

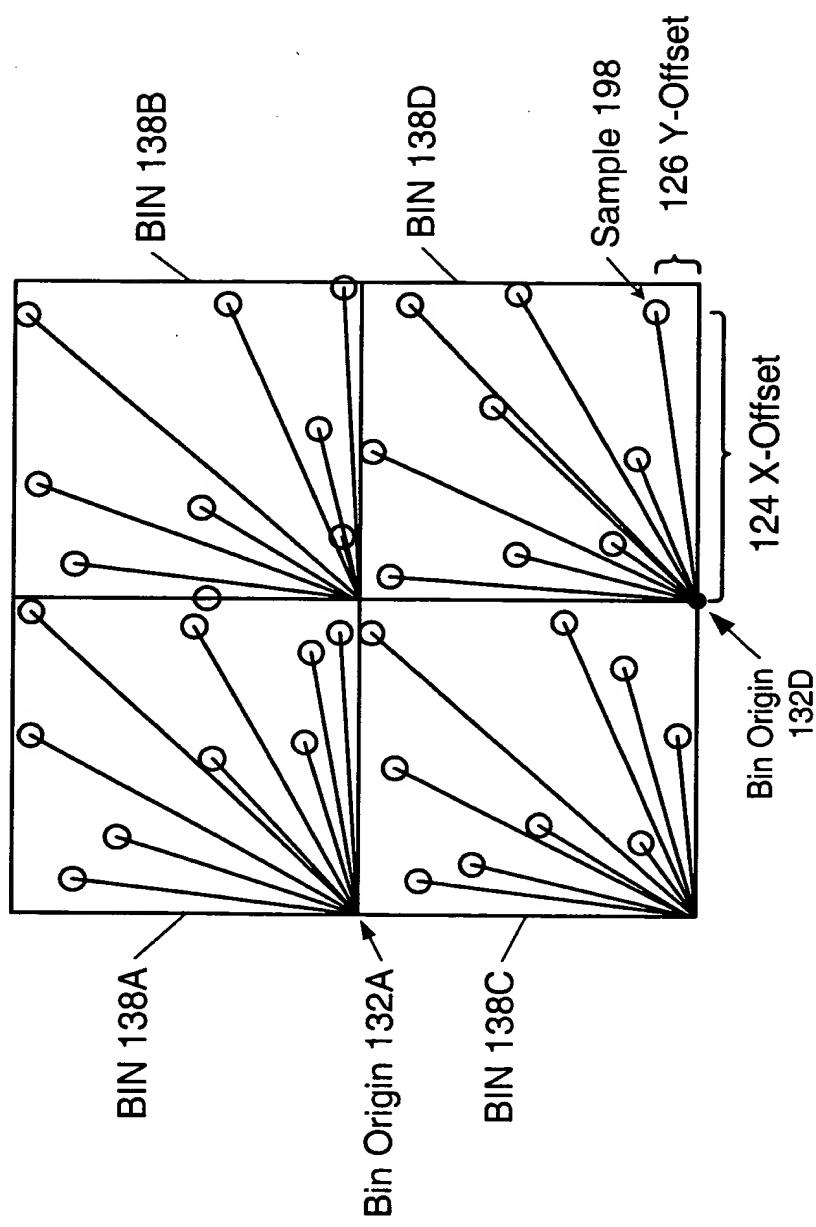


FIG. 10

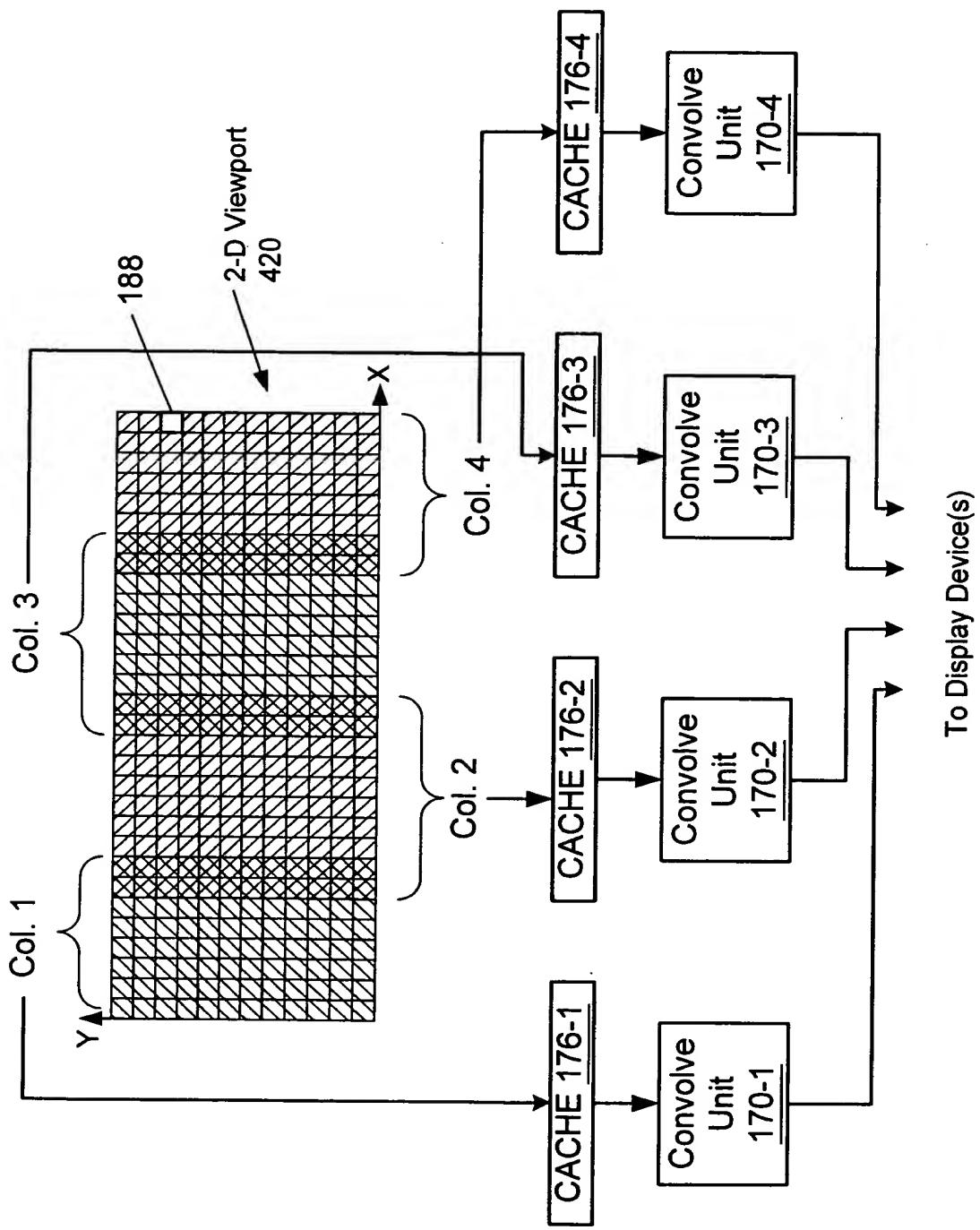


FIG. 11

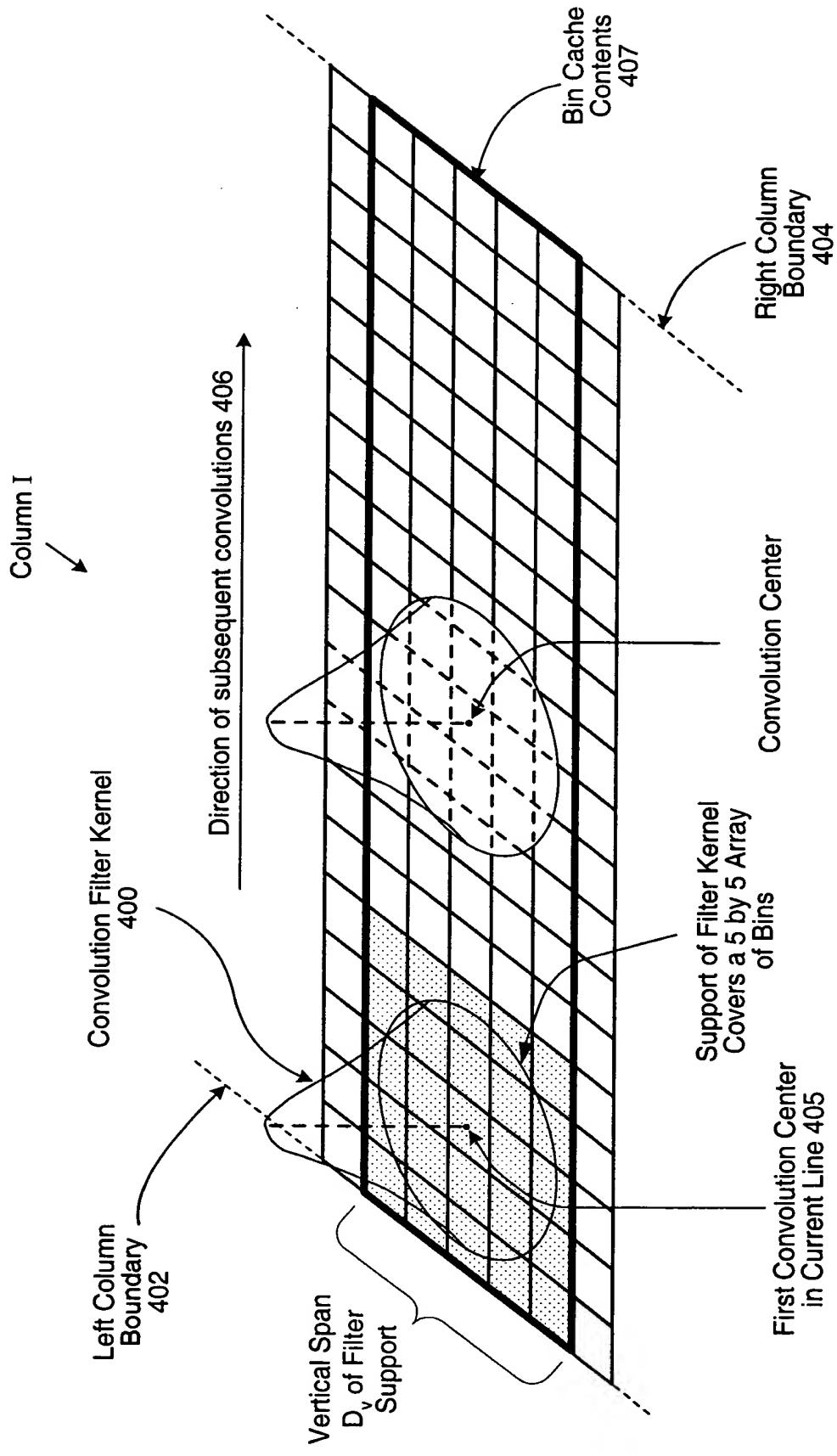


FIG. 12A

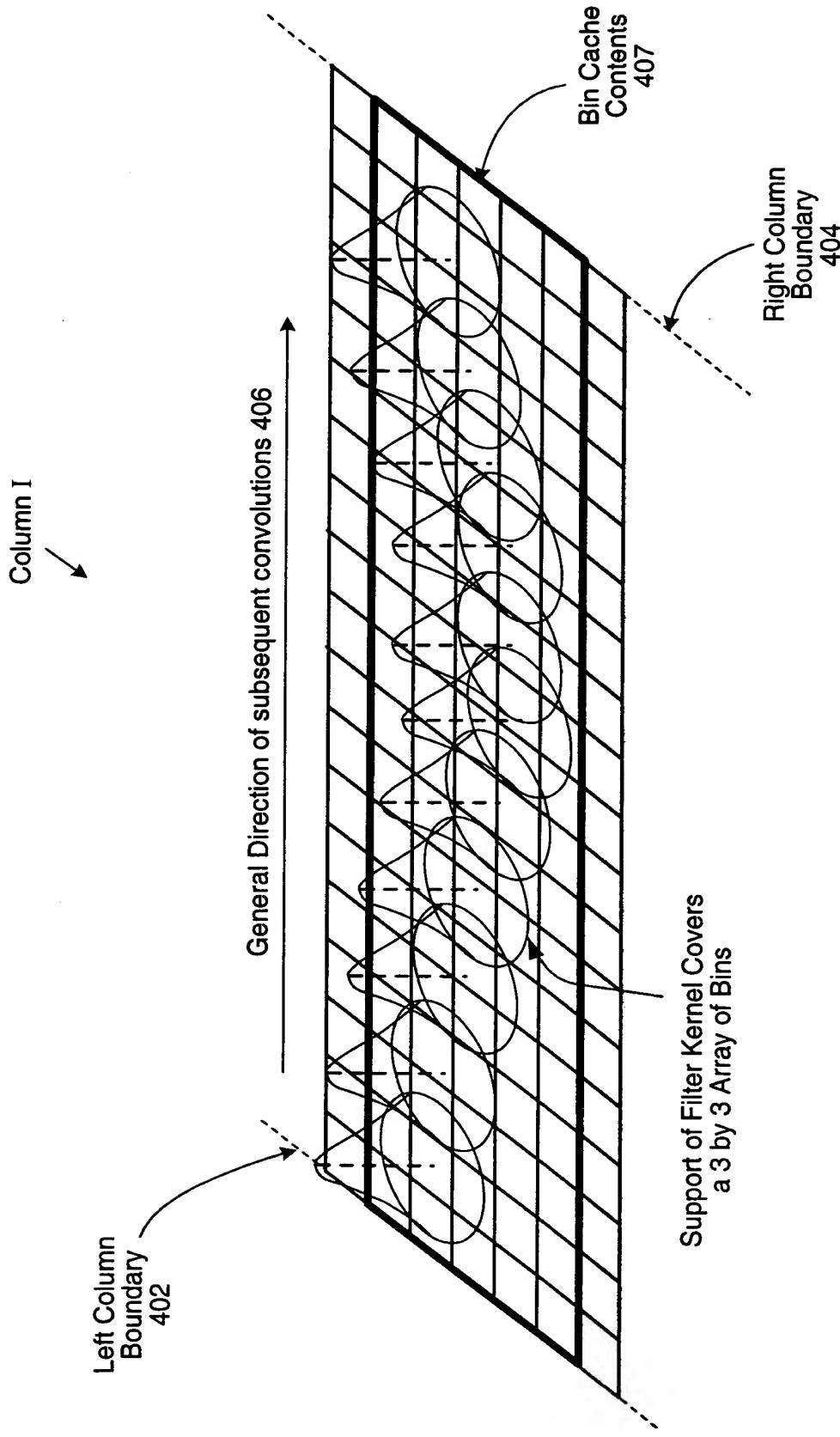


FIG. 12B

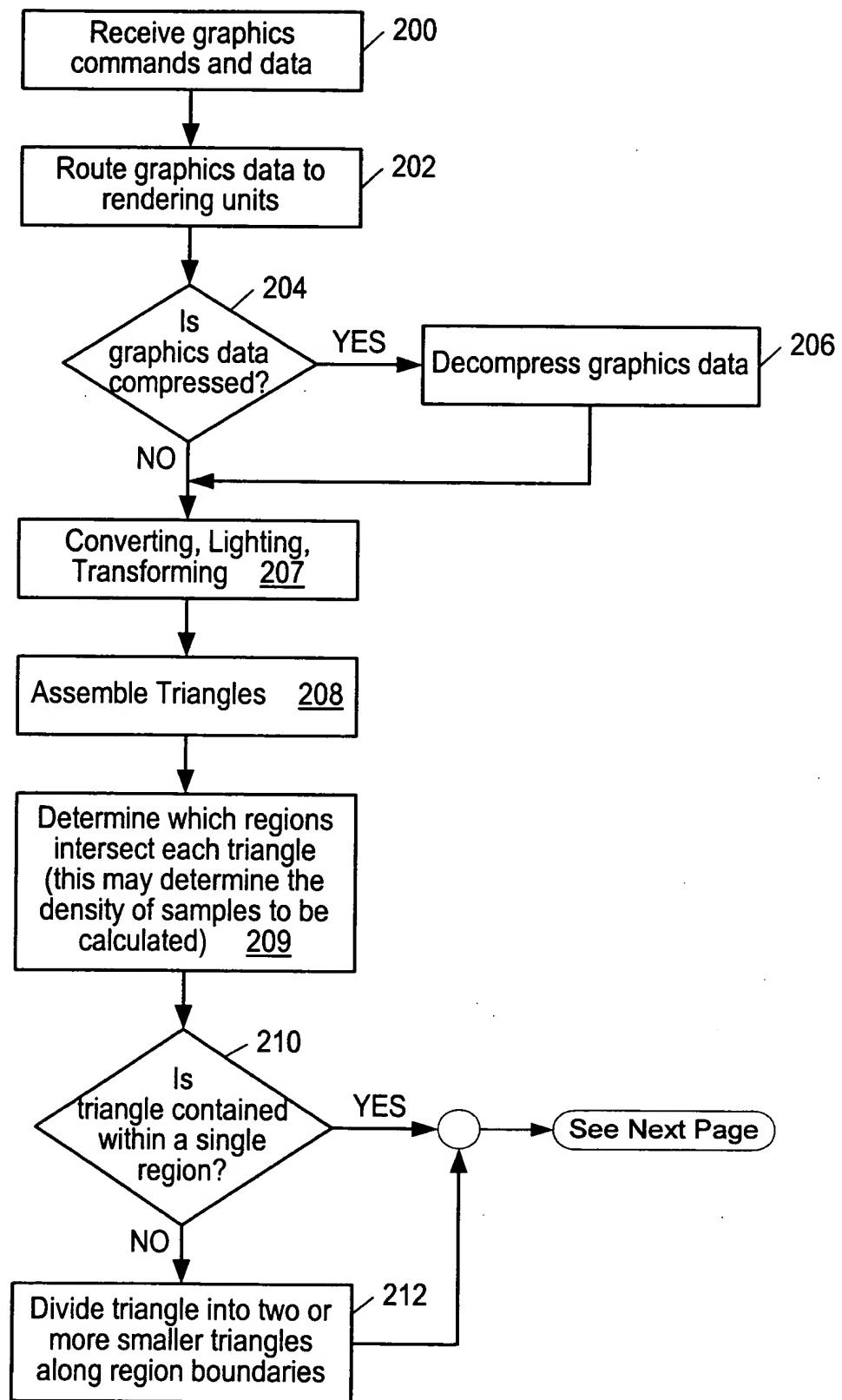


FIG. 13A

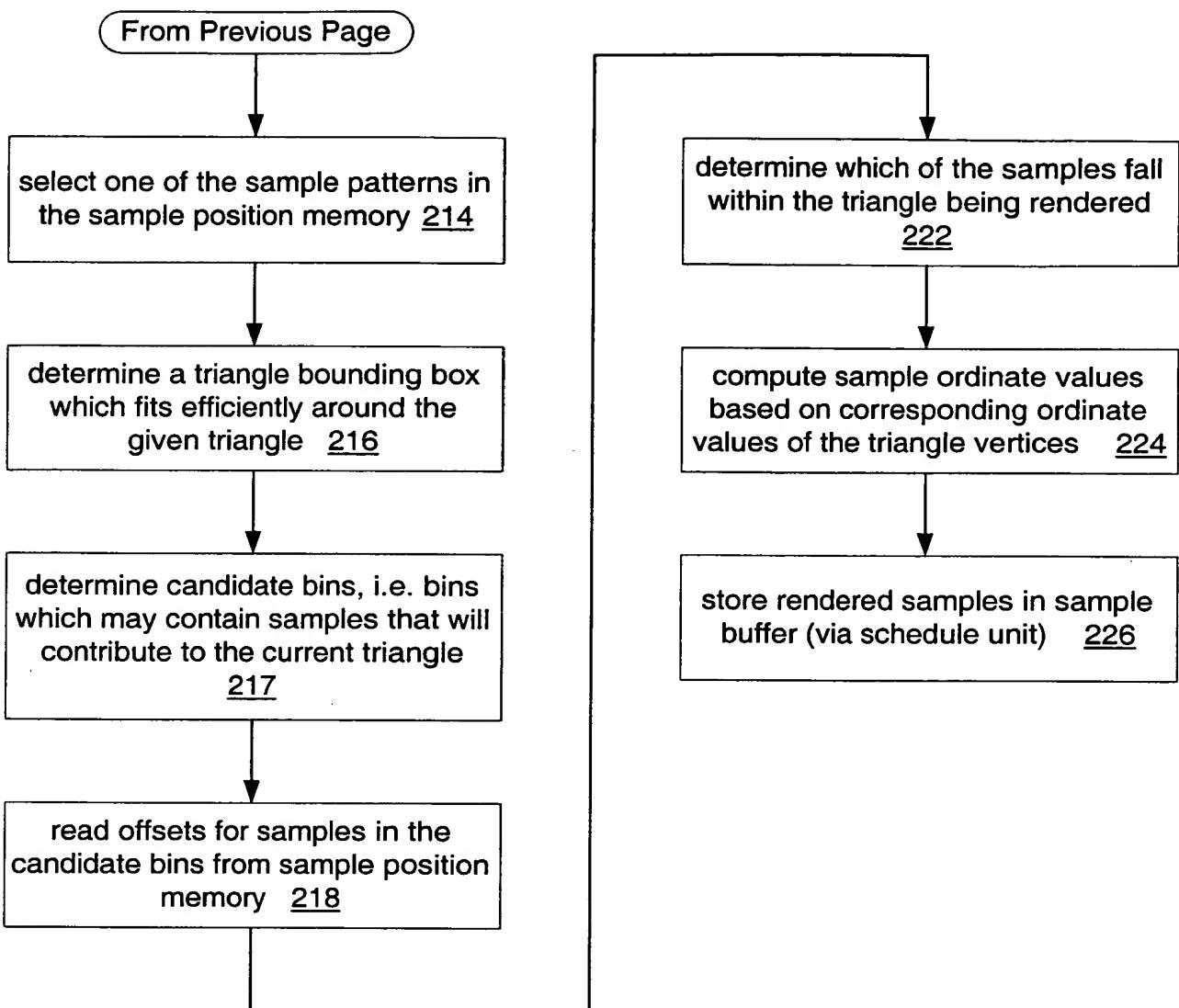


FIG. 13B

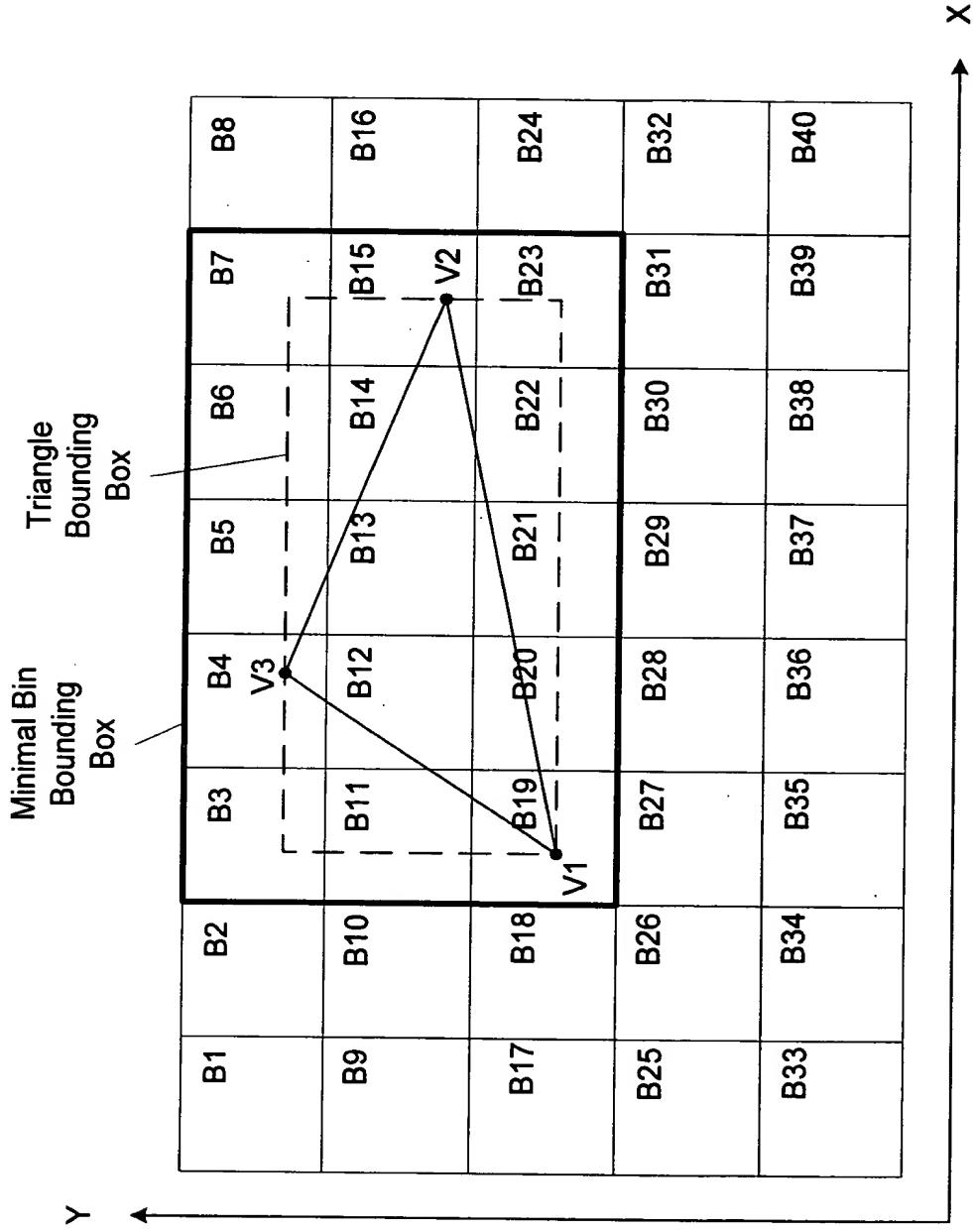
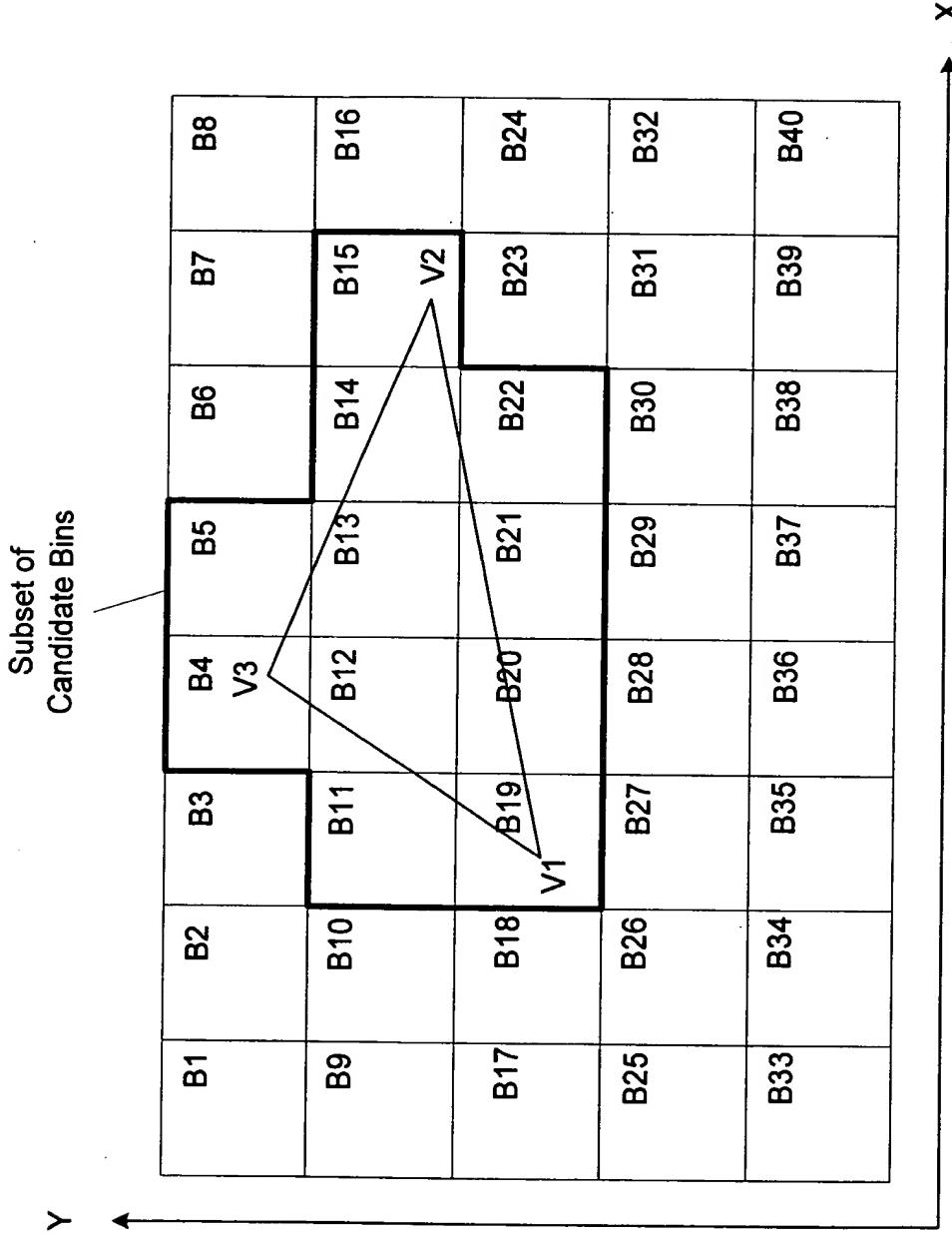


Fig. 13C

Fig. 13D



Bin Identifications

B3	B4	B5	B6	B7
B11	B12	B13	B14	B15
B19	B20	B21	B22	B22

**Minimal Bin Bounding Box
(i.e. Candidate Bins)**

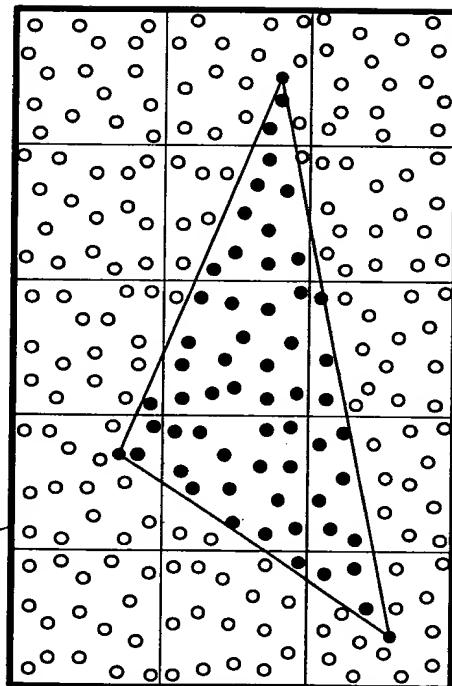


Fig. 13E

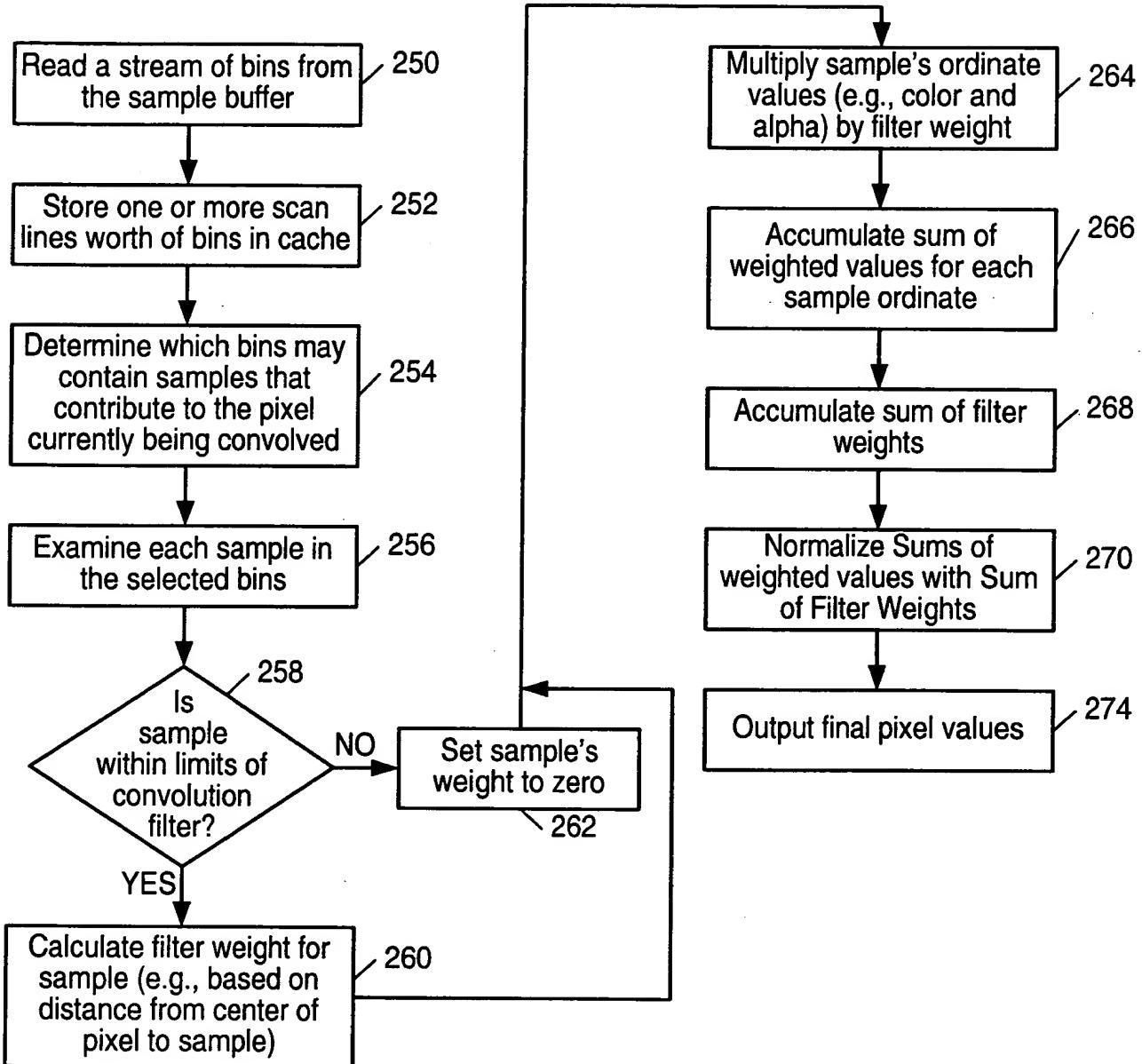
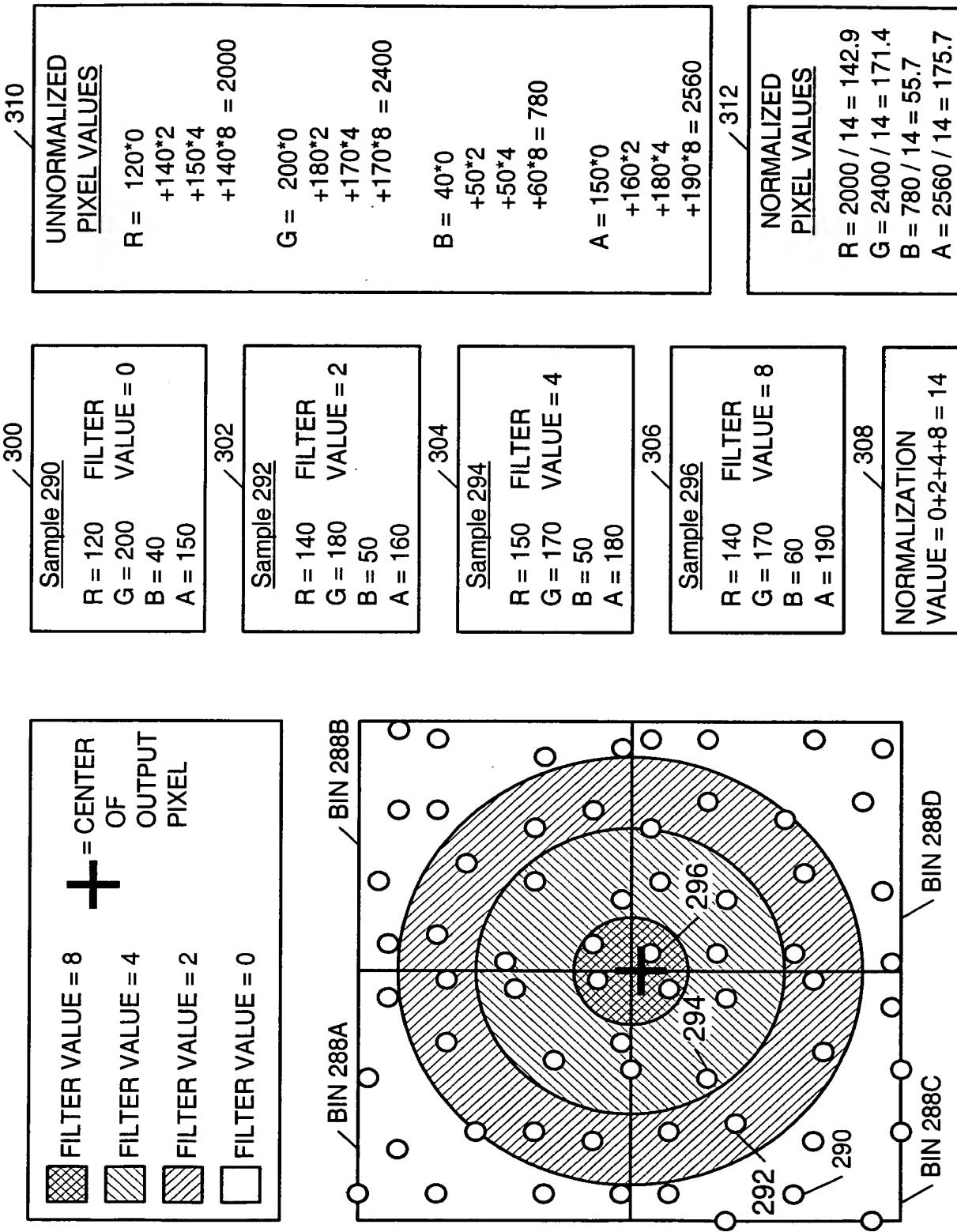


FIG. 14

FIG. 15



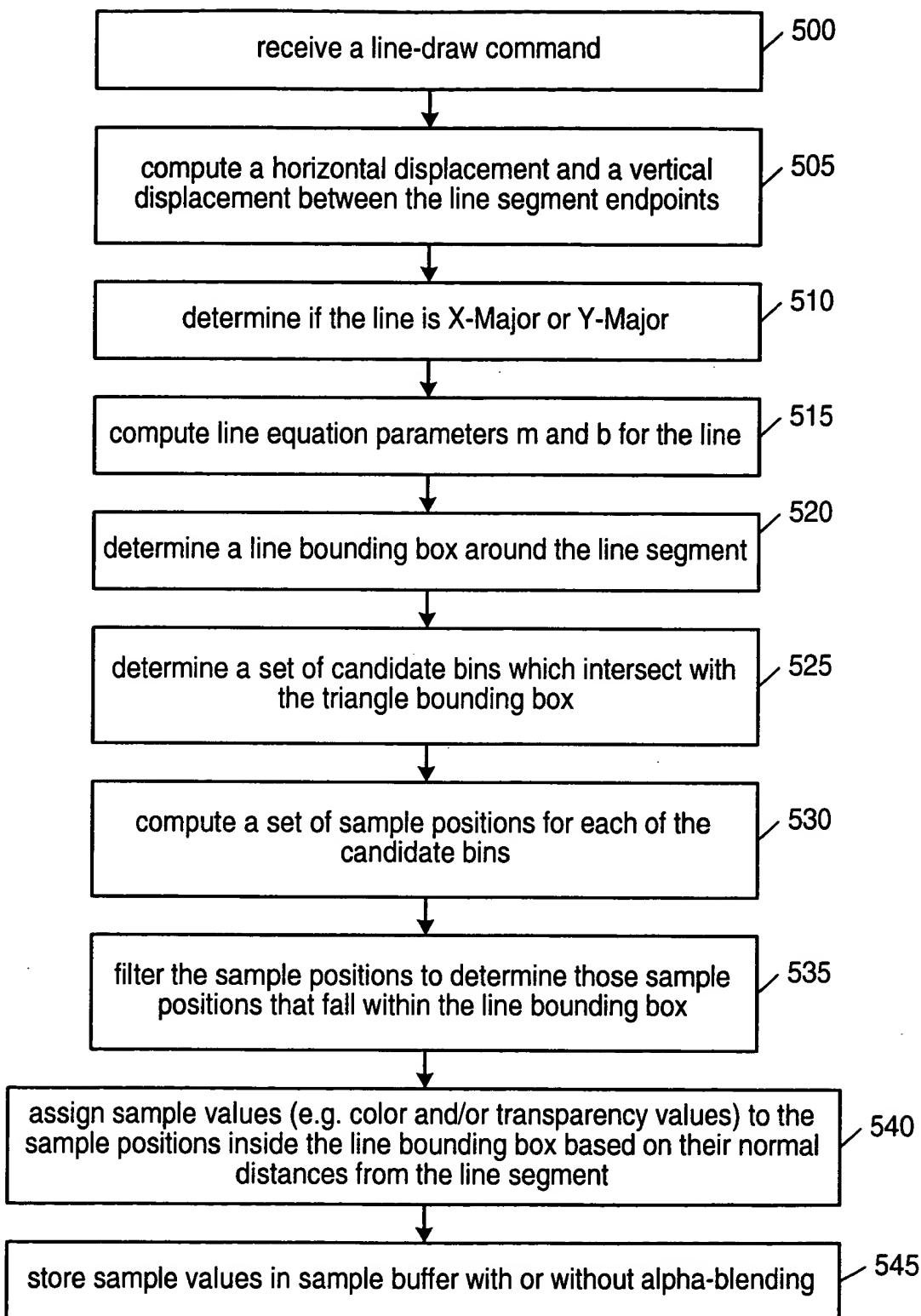


FIG. 16

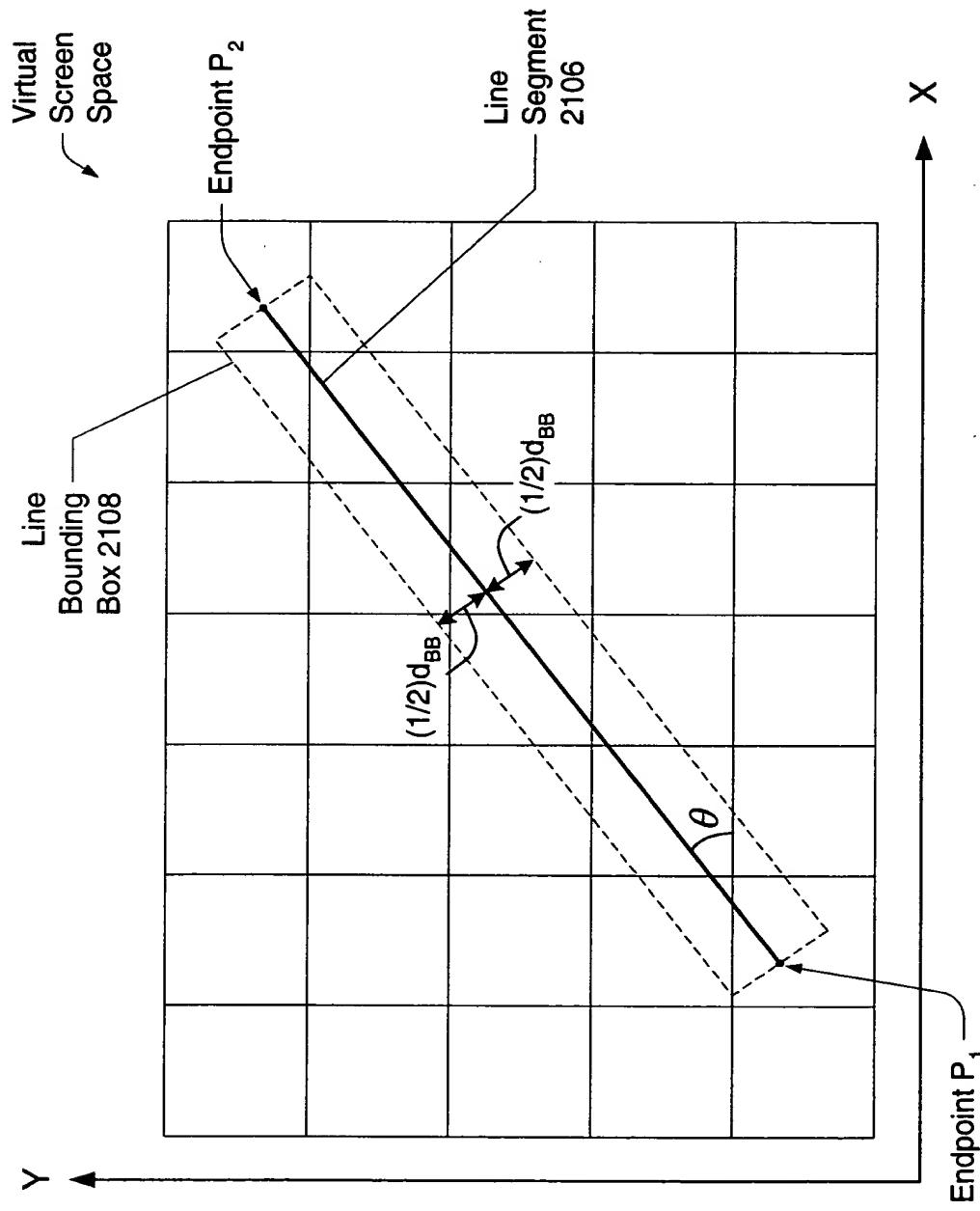


Fig. 17A

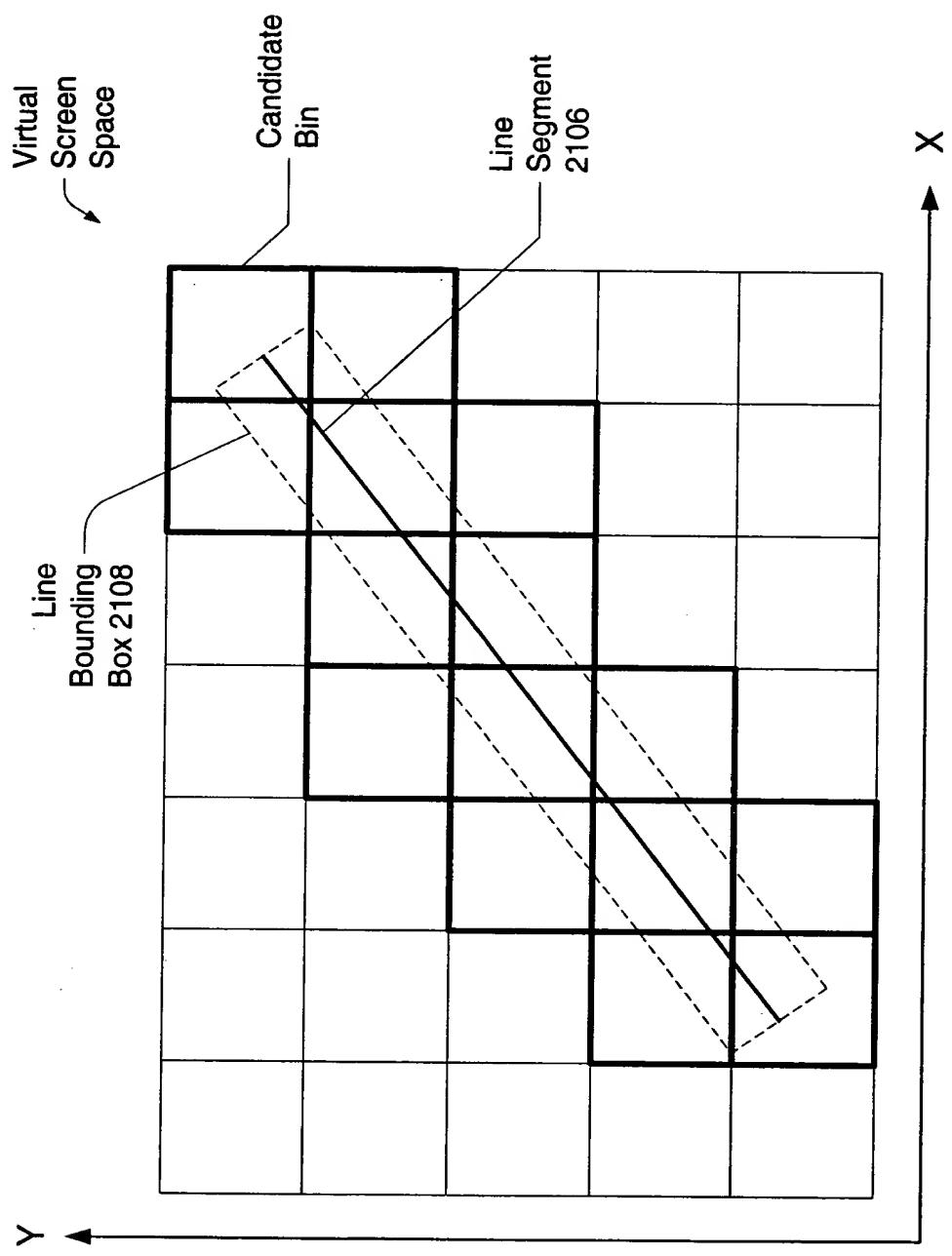


Fig. 17B

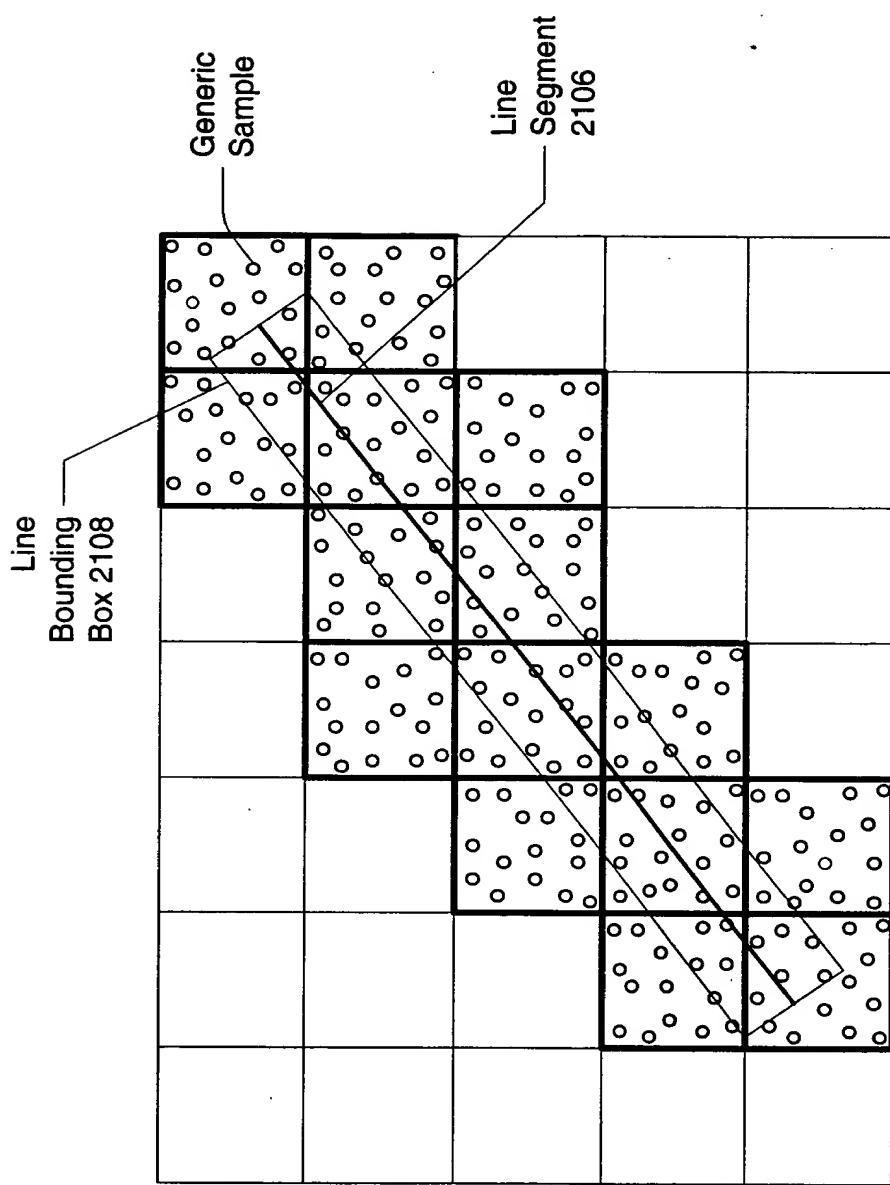


Fig. 17C

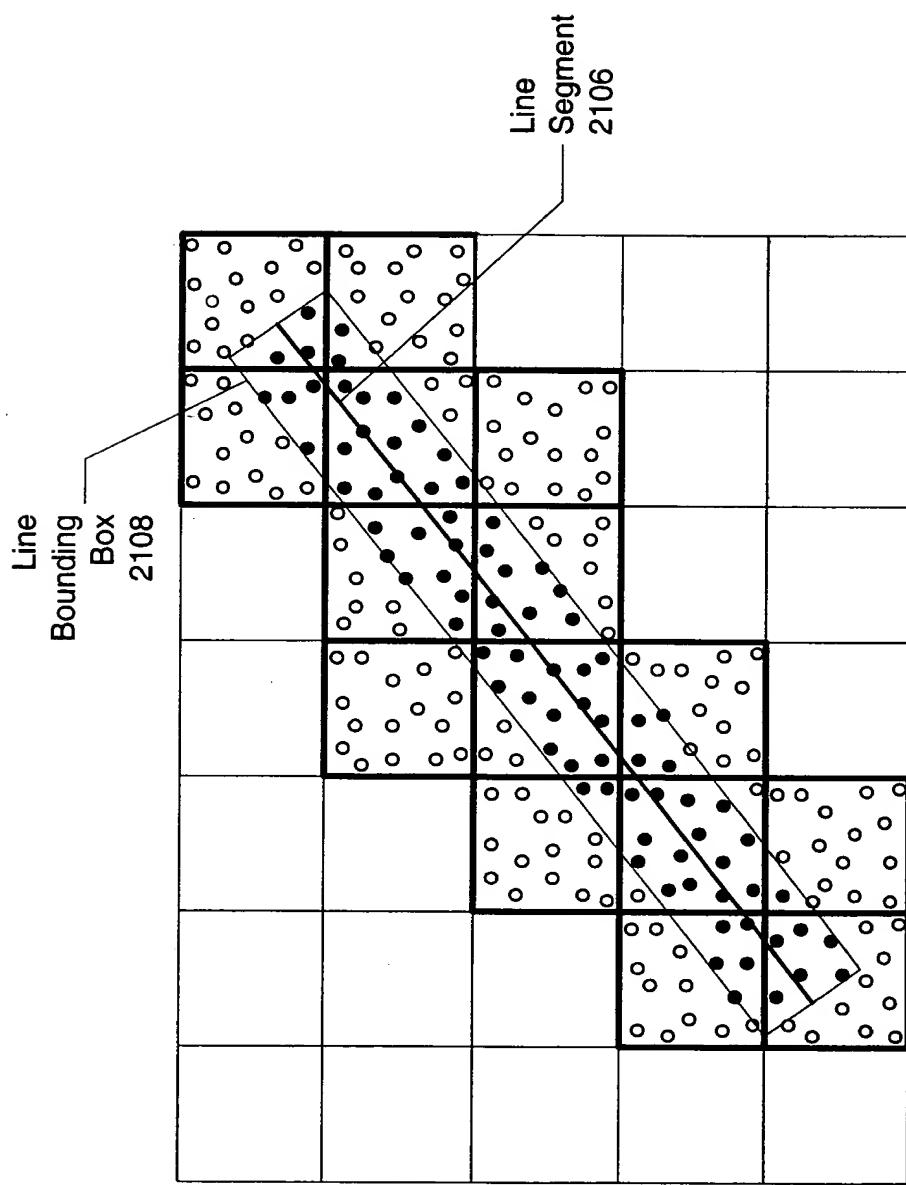


Fig. 17D

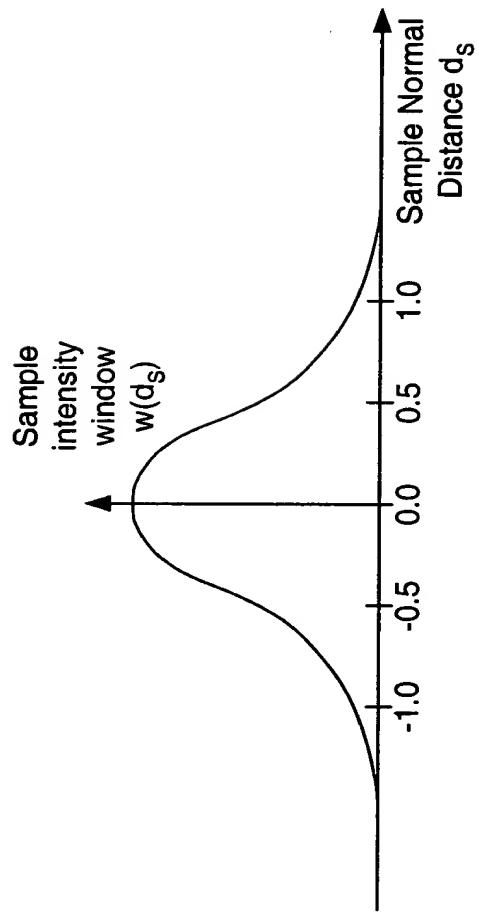


Fig. 17E

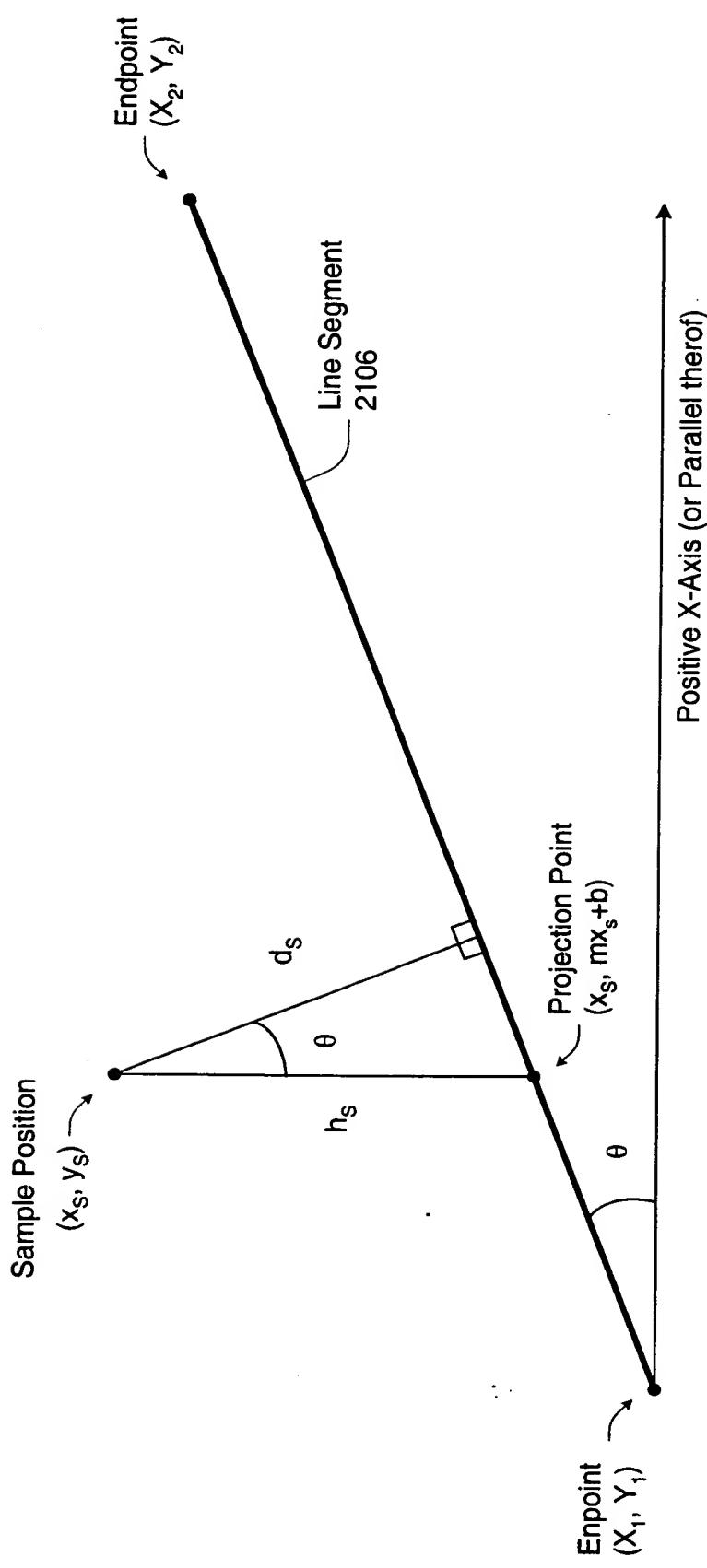


Fig. 17F

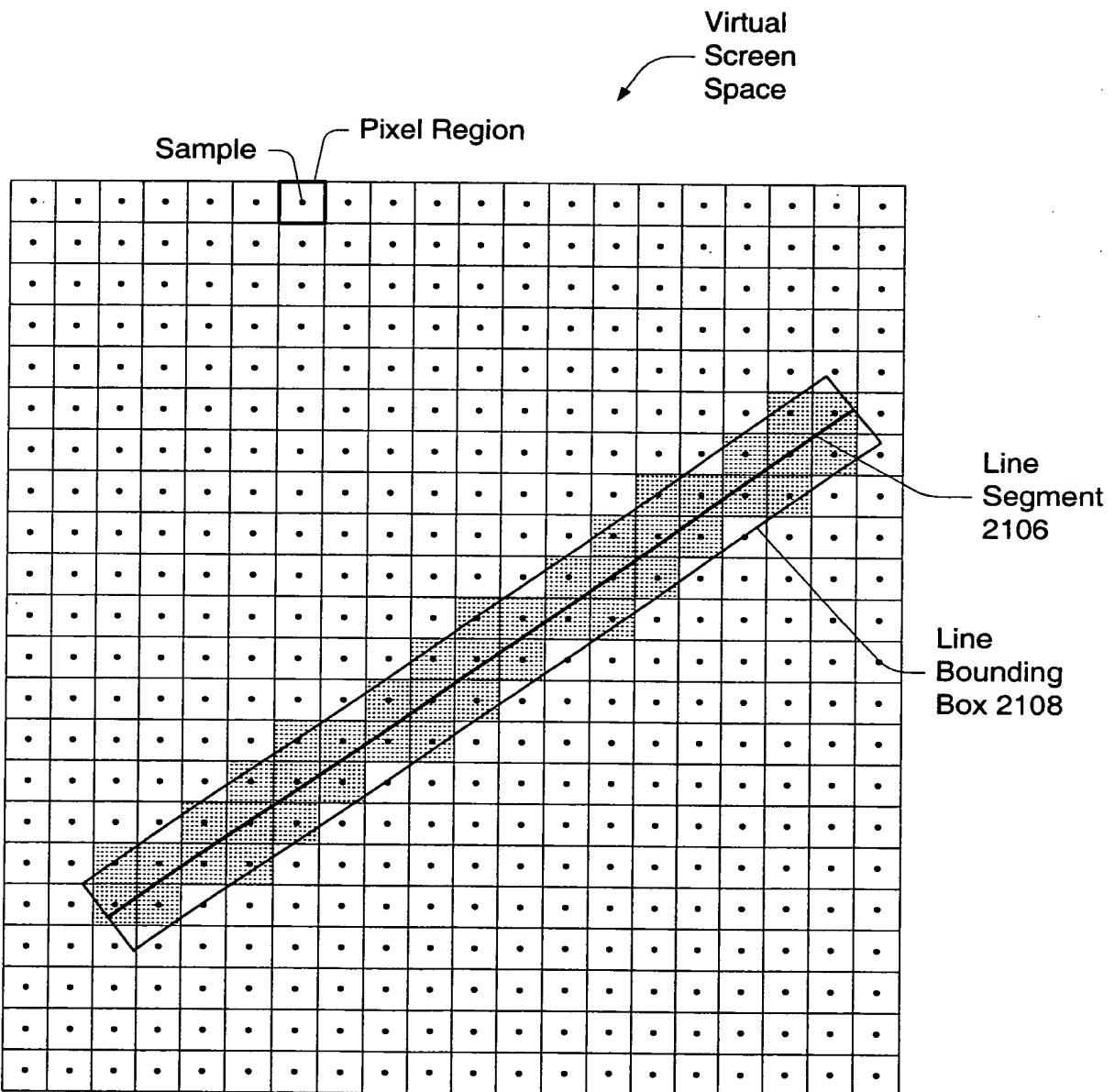


Fig. 18